DESIGN OBJECTIVES

High Voltage Detective Connector 108-32179

The product described in this document has not been fully tested to ensure conformance to the requirements outlined herein. TE Connectivity makes no representation or warranty, express or implied that the product will comply with these requirements. Further, TE Connectivity reserves the right these requirements based on the results of additional testing and evaluation. Contact TE Connectivity Engineering for further information. If necessary, this document will become the Product Specification at successful completion of testing.

1. Scope:

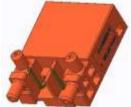
1.1 Content

This specification covers the requirements for product performance, test methods and quality assurance provisions of High Voltage Detective Connector.

MQS 2P/6P HEADER ASSY RIGHT ANGLE/VERTICAL ANGLE:

TE PN: 2322946-1/2322946-2 (6P RIGHT ANGLE) 2322949-1/2322949-2 (6P VERTICAL ANGLE) 2-2322946-1/2-2322946-2 (2P RIGHT ANGLE) 2-2322949-1/2-2322949-2 (2P VERTICAL ANGLE)





MQS 2P/6P HOUSING:

TE PN: 2322948-1/2322948-2 (6P) 2-2322948-1/2-2322948-2 (2P) Terminal: 5-963715-1 (wire size: 0.5mm²)





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A	Released	W.Z	20NOV2018	1 of 11	Hig	High Voltage Detective Connector				
LTR	REVISION RECORD	DR	DATE			_				

2. Applicable Documents:

The following documents form a part of this specification to the extent specified herein. In the event of conflict between the requirements of this specification and the product drawing, product drawing shall be taken precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

2.1 Specifications:

- A. USCAR-2-2013
- B. USCAR-37-2008
- C. GMW3172-2015
- D. GMW3191-2012
- E. DIN IEC 68 2-20
- F. IEC 60068-2-54
- G. IEC 60512-5-2
- H. IEC 60529
- I. EIA 364-70A

3. Requirements:

3.1 Design and Construction

Product shall be of the design, construction and physical dimensions specified in the applicable product drawing.

3.2 Materials

MQS 2P/6P HEADER ASSY RIGHT ANGLE/ VERTICAL ANGLE:

Housing: PPA-GF30 V0 (Zytel HTN FR52G30NH NC010)

Terminal: CuZn30 H04 Plating: Sn over Ni

MQS 2P/6P HOUSING:

PA6-GF20 V0 (Durethan BKV 20 FN01)

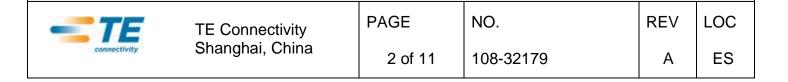
3.3 Ratings:

- A. Operating Temperature Range: Class 3 (-40 °C to +125 °C)
- B. Nominal operating voltage: 1000V DC

For application at higher voltage please contact TE Connectivity.

Current: 1A Max at 125°C

C. Vibration Range: Class 1
GWM3172-2015 9.3.1.3 Mounting Location Underhood Sprung Masses



D. Sealing range: IP XXB

3.4 Quality Assurance Provision

A. Sample Preparation:

The test samples to be used for the test shall be prepared by random selection from the current production. No sample shall be reused, unless otherwise specified.

B. Test Condition:

All the test shall be performed under any combination of the following test condition, unless otherwise specified:

Room temperature: 23±5°C Relative humidity: 45~75%

Atmospheric pressure: 860~1060 mbar



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3.5 Requirements and Procedures Summary

General Test								
Para.	Test items		quirements		Procedu	res		
3.5.1	Visual inspection		nd non-functio		Visually, Dimensionally and functionally inspected per applicable inspection plan. USCAR-2 Section 5.1.8 Visual inspection.			
3.5.2	Heat Resistance to Reflow Soldering	Note any blisters, deformation/warpage, melting or physical damage (visual inspection by 30X max magnification).			Reflow profile refers to APPENDIX 5.1			
3.5.3	Connector and/or Terminal Cycling		ate and un-ma terminal pair		USCAR-2 Section 5.1.7 Connector and/or Term		ng	
_		Me	chanical	Test				
Para.	Test items	Re	quirements		Procedu	res		
3.5.4	Terminal to Connector Insertion Force (TPA in open position)	TPA in Oper Insertion For			USCAR-2 Section 5.4.1 Insertion Force	.3 A		
3.5.5	Terminal to Connector Insertion Force (Forward stop)	F≥50N or wi	re buckling		USCAR-2 Section 5.4.1.3 A Insertion Force			
3.5.6	Terminal from Connector Retention Force- Primary lock only	0.64mm Teri	minal: F≥30N		USCAR-2 Section 5.4.1 Retention Force	.3 B		
3.5.7	Terminal from Connector Retention Force- Primary Lock and TPA/PLR	after Moi F≥60N 2. Primary	minal: + Secondary I sture Conditio + Secondary I np/Humidify a	oning, _ock	USCAR-2 Section 5.4.1 Retention Force	.3 B		
3.5.8	Connector Mating force	F≤75N			USCAR-2 Section 5.4.2 Mating Force			
3.5.9	Connector Un-mating Force	F≤75N			USCAR-2 Section 5.4.2 Un-Mating Force	2		
3.5.10	Connector to Connector Latch Retention Force	Using conne wires and ter F≥80N	ctor pairs with rminals	out	GMW3191 4.2.18 Locked Connector Disengagement Force			
3.5.11	Polarization Feature Effectiveness	3X Maximum value of mating force (60N≤F≤150N). No damage for connector and no electrical contact shall be made between male/female terminals.		USCAR-2 Section 5.4.4 Polarization Feature Effectiveness				
3.5.12	Header Pin Retention	15N Min			USCAR-2, Section 5.7.1 Header Pin Retention			
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		Е	lectrical T	est			
Para.	Test items	R	equirements	 S	Proce	dures	
3.5.13	Circuit Continuity Monitoring	There must be resistance of ar 7Ω for more tha	no instance ir ny terminal pa	n which the air exceeds	USCAR-2 Section Circuit Continuity		9
3.5.14	Dry Circuit Resistance	Contact Resista	ance 20mΩ M	lax	USCAR-2 Section Dry Circuit Resista		
3.5.15	Voltage Drop	Maximum Volta	ige Drop 50m	V	USCAR-2 Section 5.3.2 Voltage Drop		
3.5.16	Isolation Resistance	Resistance ≥ 10	00 MΩ at 1000	VDC	USCAR-2 Section Isolation Resistant		
3.5.17	Dielectric Withstanding	There shall be flash over betw circuits in caviti connector or sh	een cavities ces and the ounield.	or between Itside of the	USCAR 37, Section 5.5.2 3000VAC applied to the samples. Dielectric withstanding voltage test Un-sealed connector pairs shall be conditioned for ≥3hrs at lab ambient conditions prior to conducting dielectric strength testing.		
3.5.18	Temperature Rise	Test Current: 1A Ambient Temp: 125°C The measured temperature of the terminal pair interface must not exceed +5°C rise over ambient temperature. Contact Resistance 20mΩ Max.			EIA 364-70A Method 1 IEC 60512-5-2		
		Envi	ironmenta	al Test			
Para.	Test items	R	equirements	3	Proce	dures	
3.5.19	Mechanical Shock and Vibration	Connector func Para. 3.5.13, 3.	tion meets the	e needs of	USCAR-2 Section 5.4.6 Mechanical shock V1 GWM3172-2015 9.3.1.3 Mounting Location Underhood Sprung Masses Profile refers to APPENDIX 5.2, 5.3		
3.5.20	Thermal Shock	Connector fund Para. 3.5.13, 3. 3.5.17, 3.5.1			USCAR-2 Section Thermal Shock 300 cycles, -40°C~	- +125 ℃	
3.5.21	Temperature/ Humidity Cycling	Connector fund Para. 3.5.14, 3. 3.5.1			USCAR 2, Section Temperature 125° Profile refers to AF	C, 40 cyc	
3.5.22	High Temperature Exposure	Connector func Para. 3.5.14, 3.			USCAR 2, Section Temperature 125°		ours.
3.5.23	Protection against accidental contact, IPXXB (Finger)	No contact between the second 12mm dia. 10 N±10%			IEC 60529, section	n 12	
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		Solderability Test	
Para.	Test items	Requirements	Procedures
3.5.24	Solderability – Wetting Test	Surface must be 100% wetted, surface defects are not allowed (visual inspection by 4X to 25X magnification).	IEC 60068-2-54 (wetting balance test method) Pre-ageing: 50% of the devices: 1h steam aging by IEC 60068-2-20, chapter 4.1.1 method 1a 50% of the devices: 4h 155°C by IEC 60068-2-20, chapter 4.1.1 method 3a Solder bath temperature: 235 ± 3°C (leaded soldering) 245 ± 3°C (lead-free soldering) Dip in duration: 30sec ± 15sec Immersion depth: according to solder area of header pins
3.5.25	Solderability – De-wetting Test	De-wetting is not allowed (visual inspection by 4X to 25X magnification).	According to IEC 60068-2-20 5.2.5 Pre-aging: None Solder bath temperature: 260 ± 3°C (leaded soldering) 270 ± 3°C (lead-free soldering) Dip in duration: 2x 5 sec ± 0,5 sec Immersion depth: according to solder area of header pins

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3.6 Product Qualification Test and Sequences

Toot or over	min ation	Test Group					
Test or exa	mination	1	2	3	4	5	6
3.5.1 Visual Insp		1, 5	1, 4	1, 6	1, 4	1, 4	1, 4
3.5.2 Heat Resis	stance to Reflow		2	2	2	2	2
Soldering							
3.5.3 Connector	and/or Terminal						
Cycling							
3.5.4 Terminal to							
Insertion Force	(TPA in open	2					
position)							
3.5.5 Terminal to	Connector	3					
Insertion Force (Forward stop)	3					
3.5.6 Terminal fr	om Connector						
Retention Force-	- Primary lock	4					
only							
3.5.7 Terminal fr							
Retention Force-	- Primary Lock			5			
and TPA/PLR							
3.5.8 Connector	Mating Force			3			
	Un-mating Force			4			
3.5.10 Connecto	r to Connector		2				
Latch Retention	Force		3				
3.5.11 Polarization	on Feature				0		
Effectiveness					3		
3.5.12 Header P	in Retention					3	
3.5.13 Circuit Co							
Monitoring	,						
3.5.14 Dry Circu	it Resistance						3
3.5.15 Voltage D							
3.5.16 Isolation I							
3.5.17 Dielectric							
3.5.18 Temperat							3
3.5.19 Mechanic							<u> </u>
Vibration	ai Oriock aria						
3.5.20 Thermal \$	Shock						
3.5.21 Temperat							
Cycling	larc/r farmalty						
3.5.22 High Tem	nerature						
Exposure	iporaturo						
3.5.23 Protection	n against						
accidental conta							
(Finger)	O., II 707.D						
3.5.24 Solderabi	lity – Wetting						
3.5.25 Solderabi							
0.0.20 00luerabl	6P Connector	4	10	10	4	4	4
	6P Terminal						
Sample Size		24	- 40	24	-	-	-
-	2P Connector	5	10	10	4	4	5
	2P Terminal	10	-	10	-	-	-

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3.6 Product Qualification Test and Sequences (continued)

Test or exa	mination	Test Group						
rest or exa	IIIIIauon	7	8	9	10	11	12	13
3.5.1 Visual Insp	pection	1, 8	1, 12	1, 13	1, 12	1, 3	1, 3	1, 3
3.5.2 Heat Resis	stance to Reflow	2	2	2	2			
Soldering		2	2	2	2			
3.5.3 Connector	and/or Terminal	3	3	3	3			
Cycling		3	3	3	3			
3.5.4 Terminal t	to Connector							
Insertion Force	(TPA in open							
position)								
3.5.5 Terminal to	o Connector							
Insertion Force	(Forward stop)							
3.5.6 Terminal fi								
Retention Force	- Primary lock							
only	•							
3.5.7 Terminal fr	rom Connector							
Retention Force	- Primary Lock			12				
and TPA/PLR	•							
3.5.8 Connector	Mating Force							
	Un-mating Force							
	3.5.10 Connector to Connector							
Latch Retention	Force							
3.5.11 Polarizati	ion Feature							
Effectiveness								
3.5.12 Header F	Pin Retention							
3.5.13 Circuit Co	ontinuity	_	7					
Monitoring	•	5	7					
3.5.14 Dry Circu	it Resistance	4, 6	4, 8	4, 8	4, 8			
3.5.15 Voltage [7	9	9	9			
3.5.16 Isolation			5, 10	5, 10	5, 10			
3.5.17 Dielectric			6, 11	6, 11	6, 11			
3.5.18 Tempera	· ·		<u> </u>	<u> </u>	<u> </u>			
3.5.19 Mechanic		_						
Vibration	our orroom aria	5						
3.5.20 Thermal	Shock		7					
3.5.21 Tempera			'	_				
Cycling	13 3/1 / Williams			7				
3.5.22 High Ten	nperature							
Exposure					7			
3.5.23 Protection	n against							
accidental conta						2		
(Finger)	The state of the s					_		
	3.5.24 Solderability – Wetting						2	
	ility – De-wetting							2
212122 23.23.40	6P Connector	10	10	10	10	4	-	-
	6P Terminal	-		24	-	-	10	10
Sample Size	2P Connector	10	10	10	10	4	-	-
	2P Terminal	-	-	10	-	_	10	10
	ZF I CIIIIIII	-	-	l 10	<u> </u>	_	10	ΙŪ

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4. QUALIFICATION TEST

4.1 Sample selection

Samples shall be prepared in accordance with applicable specification.

4.2 Test sequence

Qualification test shall be conducted as sequence specified in table of section 3.6.

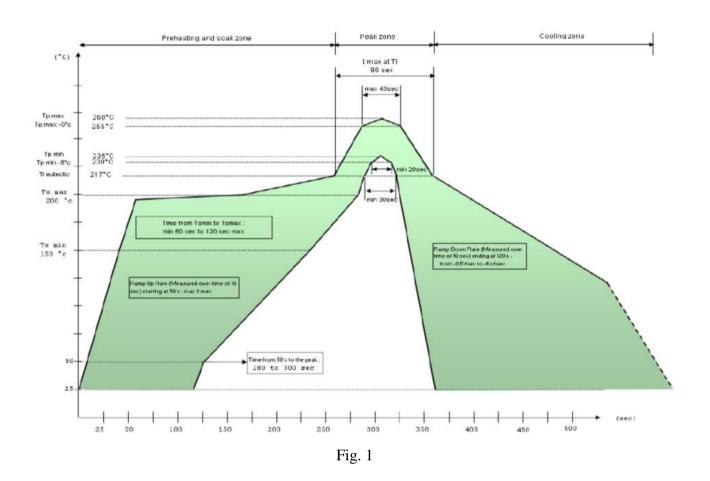
4.3 Requalification test

If changes significantly affecting form, fit or function are made to product or manufacturing process, product assurance shall co-ordinate requalification testing, consisting of all or part of original testing sequence as determined by developments, product, quality and reliability engineering.

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5. APPENDIX

5.1 Reflow Profile (see Fig. 1)



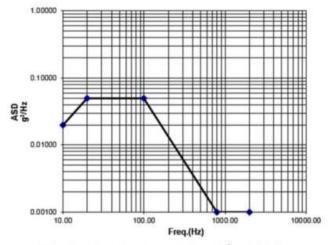
5.2 Mechanical Shock Schedule (see Fig. 2)

Vibration	Shocks	Wave	Direction	Duration	Acceleration (g)
Class	per Axis	Shape	(+/-)	(ms)	
V1	10	Half Sine Wave	Positive	5 ~ 10	35

Fig. 2

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5.3 Random Vibration Profile for Underhood Sprung Masses (see Fig. 3)



Frequency	Power Spectral Density		
10 Hz	1.9324 (m/s ²) ² /Hz = 0.0200 g ² /Hz		
20 Hz	4.8085 (m/s ²) ² /Hz = 0.0500 g ² /Hz		
100 Hz	4.8085 (m/s ²) ² /Hz = 0.0500 g ² /Hz		
800 Hz	0.0962 (m/s ²) ² /Hz = 0.0010 g ² /Hz		
2000 Hz	0.0962 (m/s ²) ² /Hz = 0.0010 g ² /Hz		

Effective Acceleration = 31.5 m/s² = 3.21 G_{RMS}

Fig. 3

5.4 Temperature/Humidity Cycling Schedule (see Fig. 4)

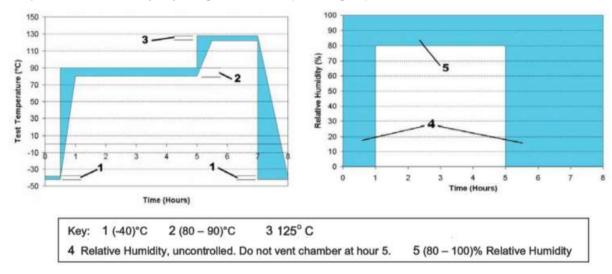


Fig. 4

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